



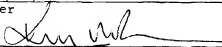


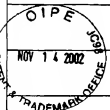



FORM PTO-1449				Atty. Docket No. XA-9387		Appln. No. 09/714,183	
LIST OF DOCUMENTS CITED BY APPLICANT							
<div style="text-align: center;">  </div>							
Applicant Hitoshi TAKEUCHI							
Filing Date November 17, 2000						Group 2877	
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Sub- class	Filing Date	
AA							
AB							
AC							
AD							
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AG							
AH							
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AK							
FOREIGN PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Country	Class	Sub- Class	Translation	
GLW	AL 59-226317	12/19/84	Japan			Partial	
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER (including author, title, date, pertinent pages, etc.)							
GLW	AR	Parity, vol. 05, No. 10, 1990-10, pp. 37-39 (with partial translation)					
	AS						
Examiner: 				Date Considered 11/26/2003			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							




FORM PFO-1449


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		Applicant Hitoshi TAKEUCHI et al.		Filing Date November 17, 2000		
		Group 2877				
U.S. PATENT DOCUMENTS						
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AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						
FOREIGN PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Country	Class	Sub-class	Translation
AL						
AM						
AN						
AO						
AP						
AQ						
OTHER (including author, title, date, pertinent pages, etc.)						
	Haig et al., "Effects of Wavefront Aberration on Visual Instrument Performance, and a Consequential Test Technique," <u>Applied Optics</u> , 2/1/87, Vol. 26, No. 3, pp. 492-500.					
	Kitano et al., "Spherical Aberration of Gradient-Index Rod Lenses," <u>Applied Optics</u> , 2/83, Vol. 22, No. 3, pp. 396-399.					
Examiner			Date Considered 11/26/2003			
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LIST OF DOCUMENTS CITED BY APPLICANT							
				Applicant Hitoshi TAKEUCHI et al.			
				Filing Date November 17, 2000		Group 2877	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
	AA	5,202,748	04/13/93	MacDonald et al.	356	360	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
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FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
	AL						
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER (including author, title, date, pertinent pages, etc.)							
	AR	Gourlay et al., "A real-time closed-loop liquid crystal adaptive optics system: first results", <u>Optics Communications</u> , Vol. 137, No. 1-3, April 15, 1997, pp. 17-21.					
	AS						
	AT						
Examiner				Date Considered 11/26/2003			
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LIST OF DOCUMENTS CITED BY APPLICANT				Applicant Hitoshi TAKEUCHI			
				Filing Date November 17, 2000		Group 2877	
				U.S. PATENT DOCUMENTS			
Examiner Initial	Document Number	Date	Name	Class	Sub-class	Filing Date	
<i>AN</i>	AA 3,973,953	8/10/76	Montgomery	96	1		
	AB 4,405,232	9/20/83	Mansell	356	121		
	AC 4,413,909	11/8/83	Pohle	356	354		
	AD 4,438,330	3/20/84	Hardy	250	201		
	AE 4,620,790	11/4/86	Hufnagel	356	124		
	AF 4,667,103	5/19/87	Watson et al.	250	332		
	AG 4,725,138	2/16/88	Wirth et al.	356	121		
	AH 5,294,971	3/15/94	Braunecker et al.	356	121		
	AI 5,300,765	4/5/94	Granger et al.	250	201.9		
	AJ 6,052,180	4/18/00	Neal et al.	356	121		
	AK 6,130,419	10/10/00	Neal	250	201.9		
<i>AN</i>	AL 6,184,974	2/6/01	Neal et al.	356	121		
FOREIGN PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Country	Class	Sub-class	Translation	
	AM						
OTHER (including author, title, date, pertinent pages, etc.)							
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U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Sub-class	Filing Date	
<i>DM</i>	AA 5,680,200	10/21/97	Sugaya et al.	355	53		
	AB 5,754,299	5/19/98	Sugaya et al.	356	401		
	AC 5,825,476	10/20/98	Abitol et al.	356	124		
	AD 5,233,174	8/3/93	Zmek	250	201.9		
	AE 5,864,381	1/26/99	Neal et al.	351	205		
	AF 5,936,720	8/10/99	Neal et al.	356	121		
	AG 5,493,391	2/20/96	Neal et al.	356	121		
	AH 4,737,621	4/12/88	Gonsiorowski et al.	250	201		
	AI 4,490,039	12/25/84	Bruckler et al.	356	121		
	AJ 5,629,765	5/13/97	Schmutz	356	121		
<i>DM</i>	AK 5,912,731	6/15/99	DeLong et al.	356	121		
FOREIGN PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Country	Class	Sub-Class	Translation	
<i>DM</i>	AL 2-238338	9/20/90	Japan			Yes	
	AM 9-49781	2/18/97	Japan			No	
	AN 10-92722	4/10/98	Japan			No	
<i>DM</i>	AO 0 833 193 A	1/4/98	Europe				
	AP						
	AQ						
OTHER (including author, title, date, pertinent pages, etc.)							
	AR						
	AS						
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FORM PTO-1449

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Applicant

Hitoshi TAKEUCHI

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2877



U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Sub-class	Filing Date
AA	6,052,180	4/18/00	Neal et al.	356	121	
AB	6,130,419	10/10/00	Neal	250	201.9	
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AE						
AF						
AG						
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